



ATTORNEY'S DOCKET NO. V0077/7192 WRM/RHW


CAU 2878
#2/IDS
2-22-02
Bell

THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Liebert et al.
Serial No: 09/836,743
Filed: April 17, 2001
For: DOSE MONITOR FOR PLASMA DOPING SYSTEM
Examiner: Not Yet Assigned
Art Unit: Not Yet Assigned

CERTIFICATE OF MAILING UNDER 37 C.F.R. §1.8(a)

The undersigned hereby certifies that this document is being placed in the United States mail with first-class postage attached, addressed to Commissioner for Patents, Washington, D.C. 20231, on the 13th day of November, 2001.


Robert H. Walat, Reg. No. 46,324

COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

Sir:

Transmitted herewith is/are the following document(s):

- ☒ Information Disclosure Statement
- ☒ Form PTO-1449 and References
- ☒ Return Receipt Postcard

If the enclosed papers are considered incomplete, the Mail Room and/or the Application Branch is respectfully requested to contact the undersigned at (617) 720-3500, Boston, Massachusetts.

No fee is required. If a fee is required, it may be charged to the account of the undersigned, Deposit Account No. 50-0896. A duplicate of this sheet is enclosed.

Respectfully Submitted,



Robert H. Walat, Reg. No. 46,324
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Robert H. Walat, Reg. No. 46,324

Commissioner for Patents
Washington, D.C. 20231

**STATEMENT FILED PURSUANT TO THE DUTY OF
DISCLOSURE UNDER 37 CFR §§1.56, 1.97 AND 1.98**

Sir:

Pursuant to the duty of disclosure under 37 C.F.R. §§1.56, 1.97 and 1.98, the Applicant requests consideration of this Information Disclosure Statement.

PART I: Compliance with 37 C.F.R. §1.97

This Information Disclosure Statement has been filed before the mailing date of a first Office Action on the merits in the above-identified case. No fee or certification is required.

PART II: Information Cited

The Applicant hereby makes of record in the above-identified application the information listed on the attached form PTO-1449 (modified). The order of presentation of the references should not be construed as an indication of the importance of the references.

The applicant would like to bring to the Examiner's attention the following co-pending applications that may contain subject matter related to this application:

<u>Serial No.</u>	<u>Filing Date</u>	<u>Title of Application</u>
09/455,550	12/06/99	Dose Monitor for Plasma Doping System
09/836,882	04/17/01	Dose Monitor for Plasma Doping System
09/916,998	07/27/01	Dose Monitor for Plasma Doping System

PART III: Remarks

Documents cited on the attached form PTO-1449 (modified) are enclosed unless otherwise indicated on the attached form PTO-1449 (modified). It is respectfully requested that:

1. The Examiner consider completely the cited information, along with any other information, in reaching a determination concerning the patentability of the present claims;
2. The enclosed form PTO-1449 be signed by the Examiner to evidence that the cited information has been fully considered by the Patent and Trademark Office during the examination of this application;
3. The citations for the information be printed on any patent which issues from this application.

By submitting this Information Disclosure Statement, the Applicant makes no representation that a search has been performed, of the extent of any search performed, or that more relevant information does not exist.

By submitting this Information Disclosure Statement, the Applicant makes no representation that the information cited in the Statement is, or is considered to be, material to patentability as defined in 37 C.F.R. §1.56(b).

By submitting this Information Disclosure Statement, the Applicant makes no representation that the information cited in the Statement is, or is considered to be, in fact, prior art as defined by 35 U.S.C. §102.

Serial No.: 09/836,743

Art Unit: Not Yet Assigned

-3-

Notwithstanding any statements by the Applicant, the Examiner is urged to form his own conclusion regarding the relevance of the cited information.

An early and favorable action is hereby requested.

Respectfully submitted,
Liebert et al., Applicant(s)

By: 

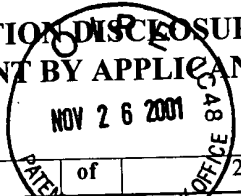
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Dated: 11/13/01
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FORM PTO-1449/A and B (Modified) INFORMATION DISCLOSURE STATEMENT BY APPLICANT NOV 26 2001 PATENT & TRADEMARK OFFICE 843		APPLICATION NO.: 09/836,743	ATTY. DOCKET NO.: V0077/7192
		FILING DATE: April 17, 2001	
		APPLICANT: Liebert et al.	
		GROUP ART UNIT: Not Yet Assigned	EXAMINER: Not Yet Assigned
Sheet	1	of	

U.S. PATENT DOCUMENTS

Examiner's Initials#	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication or of issue of Cited Document MM-DD-YYY
		Number	Kind Code		
		4,021,675		Shifrin	05/03/77
		4,135,097		Forneris et al.	01/16/79
		4,228,358		Ryding	05/23/79
		4,234,797		Ryding	05/23/79
		4,361,762		Douglas	11/30/82
		4,421,988		Robertson et al.	12/20/83
		4,433,247		Turner	02/21/84
		4,463,255		Robertson et al.	07/31/84
		4,539,217		Farley	09/03/85
		4,587,433		Farley	05/06/86
		4,595,837		Wu et al.	06/17/86
		4,744,938		Ruddy	05/17/88
		4,751,393		Corey Jr. et al.	05/16/86
		4,764,394		Conrad	08/16/88
		4,786,814		Kolondra et al.	11/22/88
		4,937,205		Nakayama et al.	06/90
		5,015,493		Gruen	05/91
		5,126,163		Chan	06/30/92
		5,206,180		Yoshida	04/93
		5,286,676		Kruger et al.	02/94
		5,289,010		Shohet	02/94
		5,354,381		Sheng	10/11/94
		5,374,456		Matossian et al.	12/94
		5,572,038		Sheng et al.	11/05/96
		5,653,811		Chan	08/05/97
		5,654,043		Shao et al.	08/05/97
		5,658,423		Angell et al.	08/19/97
		5,711,812		Chapek et al.	01/27/98
		5,728,253		Saito et al.	03/17/98
		5,814,823		Benveniste	09/29/98
		5,825,035		Mizumura et al.	10/20/98
		5,883,391		Adibi et al.	03/16/99
		5,911,832		Denholm et al.	06/15/99
		6,020,592		Liebert et al.	02/01/00
		6,050,218		Chen et al.	04/18/00

FORM PTO-1449/A and B (Modified)		APPLICATION NO.: 09/836,743	ATTY. DOCKET NO.: V0077/7192
INFORMATION DISCLOSURE STATEMENT BY APPLICANT 		FILING DATE: April 17, 2001	
		APPLICANT: Liebert et al.	
		GROUP ART UNIT: Not Yet Assigned	EXAMINER: Not Yet Assigned
Sheet	2 of 2		

FOREIGN PATENT DOCUMENTS

Examiner's Initials#	Cite No.	Foreign Patent Document			Name of Patentee or Applicant of Cited Document (not necessary)	Date of Publication of Cited Document MM-DD-YYYY	Translation (Y/N)
		Office/Country	Number	Kind Code			
		EP	0 532 283 ✓	A1	Sharp Kabushiki Kaisha	17.03.93	
		EP	0 860 854 ✓	A1	Eaton Corporation	26.08.98	
		EP	0 994 203 ✓	A2	Eaton Corporation	19.04.00	

OTHER ART - NON PATENT LITERATURE DOCUMENTS

Examiner's Initials#	Cite No.	Include name of the author (in CAPITAL LETTERS) title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, relevant page(s), volume-issue number(s), publisher, city and/or country where published.	Translation (Y/N)
		E.P. EERNISSE et al., "Ion Beam Profile Monitor," Rev. Sci. Instrum., vol. 46, No. 3 pp.266-268 (Mar. 1975)	
		D.M. JAMBA, "Dosimetry Measurement In Ion Implanters," Nuclear Instruments and Methods 189 pp.253-263, North Holland Publishing Company (1981)	
		D.M. JAMBA, "Semiconductor Measurement Technology: Some Aspects of Dose Measurement for Accurate Ion Implantation," NBS Special Publication 400-39, pp. 1-36 (Issued Jul. 1977)	
		D.M. JAMBA, Secondary Particles Collection in Ion Implantation Dose Measurement," Rev. Sci. Instrum., vol. 49, No. 5, pp. 634-638 (May 1978)	
		E.C. JONES et al., "Plasma Doping Dosimetry," IEEE Trans. on Plasma Science, Vol. 25, No. 1, February, 1997	
		Peter KELLERMAN, "PIII Dosimetry," EATON, Implant Systems Division, April 1999, pp. 1-13.	
		C.M. MCKENNA, "High Current Dosimetry Techniques," Radiation Effects, vol. 44, pp. 93-110, (1979)	

EXAMINER	DATE CONSIDERED
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#EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

*a copy of this reference is not provided as it was previously cited by or submitted to the office in a prior application and relied upon for an earlier filing date under 35 U.S.C. 120 (continuation, continuation-in-part, and divisional applications).

[NOTE - Must provide a copy of any patent, publication, other information listed, even if it was previously submitted to, or cited by, the U.S. Patent Office in an earlier application, unless the earlier application is identified by the IDS and is relied upon for an earlier filing date under 35 U.S.C. §120, and the copy was provided in the earlier application.]